

February 1992 Revised June 2001

74LVQ374

Low Voltage Octal D-Type Flip-Flop with 3-STATE Outputs

General Description

The LVQ374 is a high-speed, low-power octal D-type flip-flop featuring separate D-type inputs for each flip-flop and 3-STATE outputs for bus-oriented applications. A buffered Clock (CP) and Output Enable $(\overline{\text{OE}})$ are common to all flip-flops.

Features

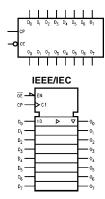
- Ideal for low power/low noise 3.3V applications
- Implements patented EMI reduction circuitry
- Available in SOIC JEDEC, SOIC EIAJ and QSOP packages
- Guaranteed simultaneous switching noise level and dynamic threshold performance
- Improved latch-up immunity
- \blacksquare Guaranteed incident wave switching into 75 $\!\Omega$
- 4 kV minimum ESD immunity
- Buffered positive edge-triggered clock
- 3-STATE outputs drive bus lines or buffer memory address registers

Ordering Code:

Order Number	Package Number	Package Description			
74LVQ374SC	M20B	20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300" Wide			
74LVQ374SJ	M20D	20-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide			
74LVQ374QSC	MQA20	20-Lead Quarter Size Outline Package (QSOP), JEDEC MO-137, 0.150" Wide			

Devices also available in Tape and Reel. Specify by appending suffix letter "X" to the ordering code.

Logic Symbols



Connection Diagram



Pin Descriptions

Pin Names	Description					
D ₀ –D ₇	Data Inputs					
CP	Clock Pulse Input					
OE	3-STATE Output Enable Input					
O ₀ -O ₇	3-STATE Outputs					

Truth Table

	Outputs		
D _n	CP	ŌE	O _n
Н	~	L	Н
L	~	L	L
Х	Х	Н	Z
U - UICH Voltage	Lovel	L = LOW Voltage	Lovel

H = HIGH Voltage Level

∠ = LOW-to-HIGH Transition

Z = High Impedance

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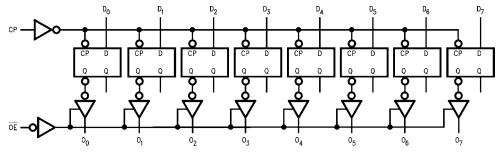
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Functional Description

The LVQ374 consists of eight edge-triggered flip-flops with individual D-type inputs and 3-STATE true outputs. The buffered clock and buffered Output Enable are common to all flip-flops. The eight flip-flops will store the state of their individual D-type inputs that meet the setup and hold time requirements on the LOW-to-HIGH Clock (CP) transition.

With the Output Enable (\overline{OE}) LOW, the contents of the eight flip-flops are available at the outputs. When the \overline{OE} is HIGH, the outputs go to the high impedance state. Operation of the \overline{OE} input does not affect the state of the flip-flops.

Logic Diagram



Please note that this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.

Absolute Maximum Ratings(Note 1)

Recommended Operating

Supply Voltage (V_{CC}) -0.5V to +7.0V

DC Input Diode Current (I_{IK})

 $V_I = -0.5V$ -20 mA $V_I = V_{CC} + 0.5V$ +20 mA

-0.5V to $V_{CC} + 0.5V$

DC Input Voltage (V_I) DC Output Diode Current (I_{OK})

 $V_O = -0.5V$ -20 mA

 $V_O = V_{CC} + 0.5V$ +20 mA DC Output Voltage (V_O) -0.5V to $V_{CC} + 0.5V$

DC Output Source

or Sink Current (I_O) $\pm 50 \text{ mA}$

DC V_{CC} or Ground Current

±400 mA $(I_{CC} \text{ or } I_{GND})$ -65°C to +150°C

Storage Temperature (T_{STG})

DC Latch-Up Source or

±300 mA Sink Current

Conditions (Note 2)

2.0V to 3.6V Supply Voltage (V_{CC})

Input Voltage (V_I) 0V to V_{CC} Output Voltage (V_O) $\rm OV$ to $\rm V_{CC}$ -40°C to $+85^{\circ}\text{C}$ Operating Temperature (T_A)

Minimum Input Edge Rate (ΔV/Δt)

V_{IN} from 0.8V to 2.0V

V_{CC} @ 3.0V 125 mV/ns

Note 1: The "Absolute Maximum Ratings" are those values beyond which the safety of the device cannot be guaranteed. The device should not be operated at these limits. The parametric values defined in the Electrical Characteristics tables are not guaranteed at the absolute maximum ratings. The "Recommended Operating Conditions" table will define the conditions for actual device operation.

Note 2: Unused inputs must be held HIGH or LOW. They may not float.

DC Electrical Characteristics

Symbol	Parameter	V _{CC}	$T_A = +25^{\circ}C$		$T_A = -40^{\circ}C \text{ to } +85^{\circ}C$	Units	Conditions	
Зушьог		(V)	Тур	Gua	aranteed Limits	Ullis	Conditions	
V _{IH}	Minimum High Level Input Voltage	3.0	1.5	2.0	2.0	٧	$V_{OUT} = 0.1V$ or $V_{CC} - 0.1V$	
V _{IL}	Maximum Low Level Input Voltage	3.0	1.5	0.8	0.8	٧	$V_{OUT} = 0.1V$ or $V_{CC} - 0.1V$	
V _{OH}	Minimum High Level	3.0	2.99	2.9	2.9	V	I _{OUT} = -50 μA	
	Output Voltage	3.0		2.58	2.48	V	$V_{IN} = V_{IL}$ or V_{IH} (Note 3) $I_{OH} = -12$ mA	
V _{OL}	Maximum Low Level	3.0	0.002	0.1	0.1	V	I _{OUT} = 50 μA	
	Output Voltage	3.0		0.36	0.44	V	$V_{IN} = V_{IL} \text{ or } V_{IH} \text{ (Note 3)}$ $I_{OL} = 12 \text{ mA}$	
I _{IN}	Maximum Input Leakage Current	3.6		±0.1	±1.0	μΑ	V _I = V _{CC} , GND	
I _{OLD}	Minimum Dynamic	3.6			36	mA	V _{OLD} = 0.8V Max (Note 5)	
I _{OHD}	Output Current (Note 4)	3.6			-25	mA	V _{OHD} = 2.0V Min (Note 5)	
I _{CC}	Maximum Quiescent Supply Current	3.6		4.0	40.0	μА	V _{IN} = V _{CC} or GND	
I _{OZ}	Maximum 3-STATE Leakage Current	3.6		±0.25	±2.5	μА	V_{I} (OE) = V_{IL} , V_{IH} V_{I} = V_{CC} , GND V_{O} = V_{CC} , GND	
V _{OLP}	Quiet Output Maximum Dynamic V _{OL}	3.3	0.5	0.8		V	(Note 6)(Note 7)	
V _{OLV}	Quiet Output Minimum Dynamic V _{OL}	3.3	-0.3	-0.8		V	(Note 6)(Note 7)	
V _{IHD}	Maximum High Level Dynamic Input Voltage	3.3	1.7	2.0		V	(Note 6)(Note 8)	
V _{ILD}	Maximum Low Level Dynamic Input Voltage	3.3	1.6	0.8		V	(Note 6)(Note 8)	

Note 3: All outputs loaded; thresholds on input associated with output under test.

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Note 4: Maximum test duration 2.0 ms, one output loaded at a time.

Note 5: Incident wave switching on transmission lines with impedances as low as 75Ω for commercial temperature range is guaranteed for 74LVQ.

Note 6: Worst case package.

Note 7: Max number of outputs defined as (n). Data inputs are driven 0V to 3.3V; one output at GND.

Note 8: Max number of Data Inputs (n) switching. (n-1) inputs switching 0V to 3.3V. Input-under-test switching: 3.3V to threshold (V_{ILD}) , 0V to threshold (V_{IHD}) , f = 1 MHz.

AC Electrical Characteristics

Symbol	Parameter	v _{cc}	$T_A = +25$ °C $C_L = 50 \text{ pF}$			$T_A = -40^{\circ}\text{C to } +85^{\circ}\text{C}$ $C_L = 50 \text{ pF}$		Units
		(V)	Min	Тур	Max	Min	Max	
f _{MAX}	Maximum Clock Frequency	2.7	55			50		MHz
		3.3 ± 0.3	75			70		IVITZ
t _{PLH}	Propagation Delay	2.7	3.0	11.4	18.3	3.0	19.0	ns
t _{PHL}	CP to O _n	3.3 ± 0.3	3.0	9.5	13.0	3.0	13.5	115
t _{PZL}	Output Enable Time	2.7	3.0	11.4	18.3	3.0	19.0	ns
t_{PZH}		3.3 ± 0.3	3.0	9.5	13.0	3.0	13.5	115
t _{PHZ}	Output Disable Time	2.7	1.0	11.4	20.4	1.0	21.0	ns
t _{PLZ}	1	3.3 ± 0.3	1.0	9.5	14.5	1.0	15.0	115
toshl	Output to Output Skew (Note 9)	2.7		1.0	1.5		1.5	ns
toslh	CP to O _n	3.3 ± 0.3		1.0	1.5		1.5	115

Note 9: Skew is defined as the absolute value of the difference between the actual propagation delay for any two separate outputs of the same device. The specification applies to any outputs switching in the same direction, either HIGH-to-LOW (t_{OSHL}) or LOW-to-HIGH (t_{OSLH}). Parameter guaranteed by design.

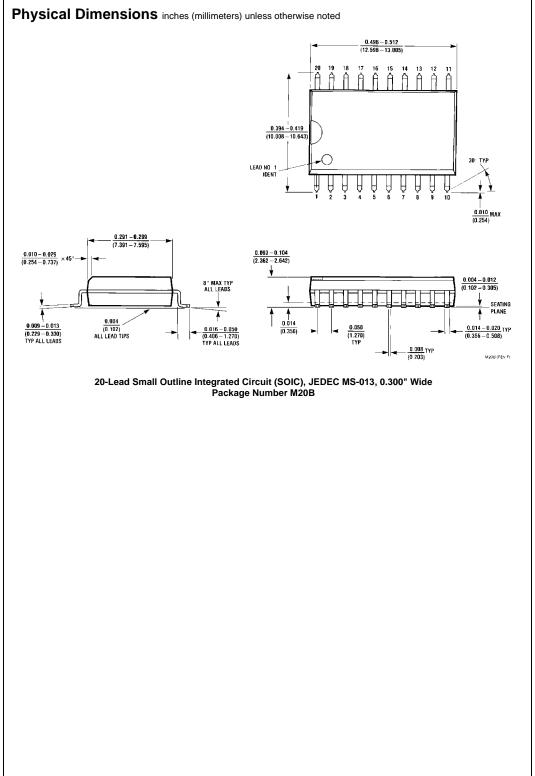
AC Operating Requirements

Symbol Parameter		T _A = +25		· ·			
		V _{CC}	C _L = 50 pF		C _L = 50 pF	Units	
		(V)	Тур	Guara	nteed Wilnimum		
t _S	Setup Time, HIGH or LOW	2.7	0	4.0	4.5	ns	
	D _n to CP	3.3 ± 0.3	0	3.0	3.0	110	
t _H	Hold Time, HIGH or LOW	2.7	0	1.5	1.5	ns	
	D _n to CP	3.3 ± 0.3	0	1.5	1.5	115	
t _W	CP Pulse Width,	2.7	2.4	5.0	6.0	ns	
	HIGH or LOW	3.3 ± 0.3	2.0	4.0	4.0	115	

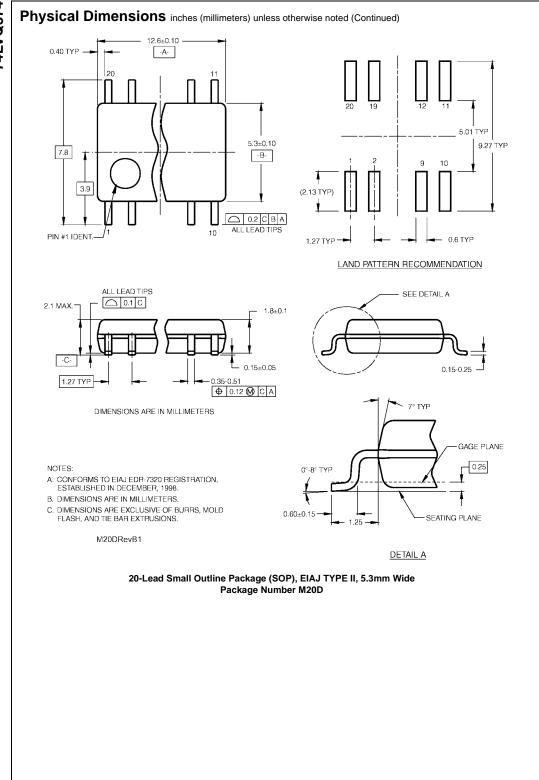
Capacitance

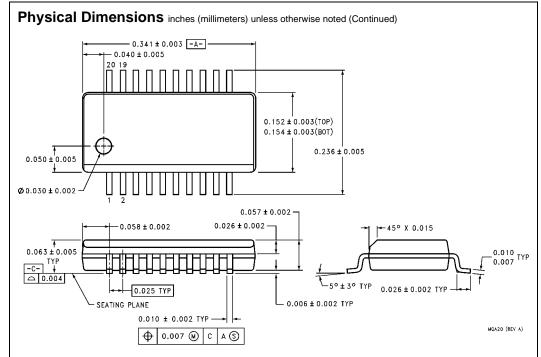
Symbol	Parameter	Тур	Units	Conditions
C _{IN}	Input Capacitance	4.5	pF	V _{CC} = Open
C _{PD} (Note 10)	Power Dissipation Capacitance	39	pF	V _{CC} = 3.3V

Note 10: C_{PD} is measured at 10 MHz.



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20-Lead Quarter Size Outline Package (QSOP), JEDEC MO-137, 0.150" Wide Package Number MQA20

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